## **Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings of claims in the application:

## **Listing of Claims:**

- 1-5. Canceled
- 6. (Original) A method of detecting defective operation of an electro-optical device, the method comprising:

disposing a polymer dispersed liquid crystal (PDLC) overlying and separated from an underlying electro-optical device by an air gap, the PDLC having a polymer matrix formed by the cross-linking of a polyacrylate resin and a polyisocyanate resin, and having a liquid crystal exhibiting a minimum bulk resistivity of 1×10<sup>12</sup> ohm.cm and a voltage holding ratio (VHR) of 98% or greater;

applying a voltage to a transparent electrode overlying the PDLC while illuminating the PDLC; and

detecting a changed intensity of light transmitted by the PDLC.

- 7. (Original) The method of claim 6 wherein the PDLC is disposed over a glass substrate bearing a thin film transistor.
- 8. (Original) The method of claim 6 wherein the changed intensity of light is detected by reflection of the incident light by a mirror.
- 9. (Original) The method of claim 6 wherein the PDLC comprises a ratio of liquid crystal to polymer of between about 50/50 and 70/30 (wt/wt).
- 10. (Original) The method of claim 6 wherein the applied voltage is between about 100-320 V across an air gap of at least 5  $\mu$ m.

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- 11. (Original) The method of claim 6 wherein the polyacrylate resin is selected from the group consisting of Paraloid AU1033 available from Rohm and Haas, and Doresco TA45-8 or Doresco TA65-1 available from Dock Resins.
- 12. (Original) The method of claim 6 wherein the polyisocyanate resin comprises an aliphatic polyisocyanate such as Desmodur N-75 from Bayer Polymers.
- 13. (Original) The method of claim 6 wherein the liquid crystal is selected from the TL series available from EM Industries.
- 14. (Original) An apparatus for inspecting a semiconductor device, the apparatus comprising:
  - a support for a semiconductor device;
- an electro-optic modulator separated from the support by an air gap, the electro-optic modulator comprising,
  - a mirror disposed proximate to the support,
  - a transparent electrode distal from the support, and
- a polymer dispersed liquid crystal (PDLC) sensor material disposed between the transparent electrode and the mirror, the PDLC having a polymer matrix formed by the crosslinking of a polyacrylate resin and a polyisocyanate resin, and a liquid crystal exhibiting a minimum bulk resistivity of 1×10<sup>12</sup> ohm.cm and a voltage holding ratio (VHR) of 98% or greater;
- a light source configured to illuminate the PDLC material during application of a voltage to the transparent electrode; and
  - a detector configured to detect intensity of light reflected by the mirror.
- 15. (Original) The apparatus of claim 14 wherein the support comprises a support for a workpiece bearing a thin film transistor.

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- 16. (Original) The apparatus of claim 14 wherein the air gap has a width of between about 5-30  $\mu$ m, and a voltage of about 100-320 V is configured to be applied to the transparent electrode.
- 17. (Original) The apparatus of claim 14 wherein the liquid crystal is selected from the TL series available from EM Industries.